TOSHIBA FIELD EFFECT TRANSISTOR SILICON N CHANNEL MOS TYPE

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HIGH SPEED SWITCHING APPLICATIONS. ANALOG SWITCH APPLICATIONS.

- High Input Impedance. •
- Low Gate Threshold Voltage
- **Excellent Switching Times**
- : $V_{th} = 0.5 \sim 1.5 V$
- : $t_{on} = 0.16 \mu s$ (typ.) $t_{off} = 0.15 \mu s$ (typ.)

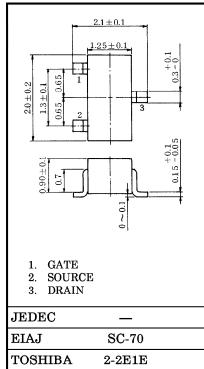
- Small Package.
- Enhancement-Mode

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Drain-Source Voltage	V _{DS}	20	v	
Gate-Source Voltage	VGSS	10	v	
DC Drain Current	ID	100	mA	
Drain Power Dissipation	PD	100	mW	
Channel Temperature	T _{ch}	150	°C	
Storage Temperature Range	T_{stg}	$-55 \sim 150$	°C	

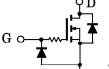
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ELECTRICAL CHARACTERISTICS (Ta = 25°C)



Weight : 0.006g

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CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		IGSS	$V_{GS}=10V, V_{DS}=0$	_	_	1	μA
Drain-Source Breakdown Voltage		V _{(BR)DSS}	$I_{D} = 100 \mu A, V_{GS} = 0$	20	_	_	V
Drain Cut-off Current		IDSS	$V_{DS}=20V, V_{GS}=0$	—	_	1	μA
Gate Threshold V	oltage	v_{th}	$V_{DS}=3V$, $I_{D}=0.1mA$	0.5	_	1.5	V
Forward Transfer Admittance		$ Y_{fs} $	$V_{DS}=3V$, $I_{D}=10mA$	25	50	_	mS
Drain-Source ON Resistance		R _{DS} (ON)	$I_{D} = 10 mA$, $V_{GS} = 2.5 V$	_	8	12	Ω
Input Capacitance		Ciss	$V_{DS}=3V, V_{GS}=0, f=1MHz$	_	8.5	_	pF
Reverse Transfer	Capacitance	C _{rss}	$V_{DS}=3V$, $V_{GS}=0$, f=1MHz	_	3.3	—	pF
Output Capacitance		Coss	$V_{DS}=3V, V_{GS}=0, f=1MHz$	_	9.3	_	pF
Switching Time	Turn-on Time	t _{on}	$V_{DD}=3V$, $I_{D}=10mA$ $V_{GS}=0\sim2.5V$	_	0.16		μs
	Turn-off Time	toff	$V_{DD}=3V, I_{D}=10mA$ VGS=0~2.5V		0.15		μs



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-THIS TRANSISTOR ELECTROSTATIC SENSITIVE DEVICE. PLEASE HANDLE WITH CAUSHON.

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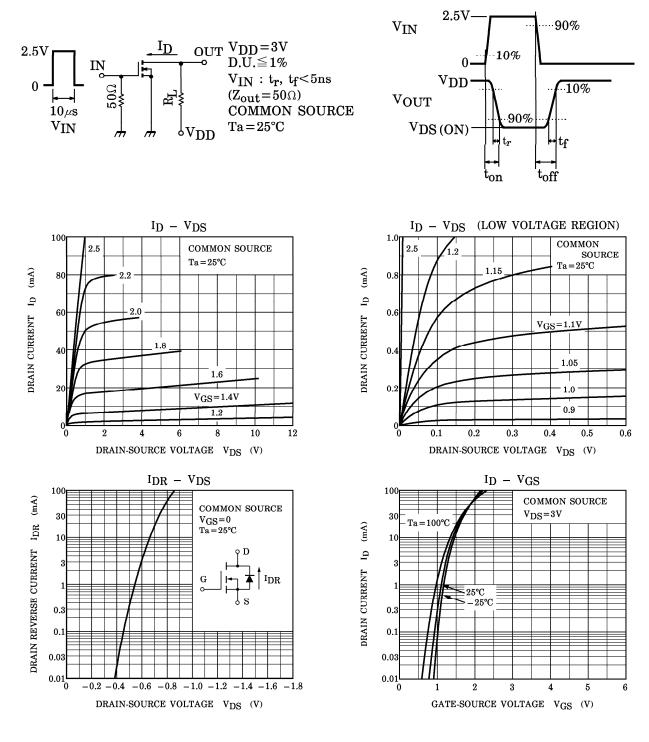
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1997-04-10

Unit in mm

SWITCHING TIME TEST CIRCUIT



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